Microchip Technology - A42MX16-3PQG208 Datasheet

Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

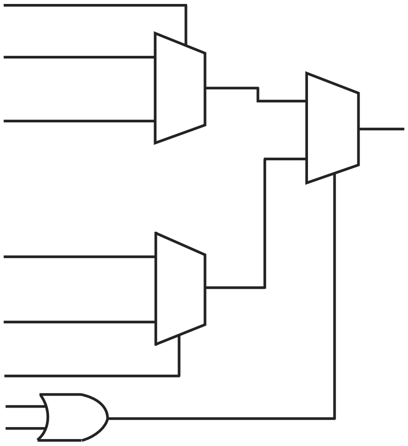
Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	140
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-3pqg208

Email: info@E-XFL.COM Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Figures

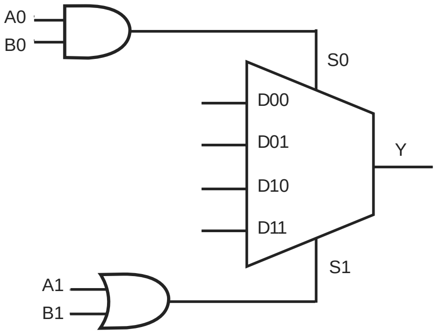
Tables

Figure 2 • **42MX C-Module Implementation**



The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

Figure 3 • **42MX C-Module Implementation**



- VCCA = Power supply in volts (V)
- F = Switching frequency in megahertz (MHz)

3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring ICCactive at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

3.4.5 C_{EQ} Values for Microsemi MX FPGAs

Modules (C_{EQM})3.5

Input Buffers (C_{EQI})6.9

Output Buffers (C_{EQO})18.2

Routed Array Clock Buffer Loads (C_{EQCR})1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\text{Power} = \text{VCCA}^2 \; *[(m \times C_{EQM} * f_m)_{\text{modules}} + (n * C_{EQI} * f_n)_{\text{inputs}} + {}^{-}(p*(C_{EQO} + C_L)*f_p)_{\text{outputs}} +$$

$$0.5*(q_1 * C_{EQCR} * f_{q1})_{\text{routed\_Clk1}} + (r_{1*} f_{q1})_{\text{routed\_Clk1}} +$$

$$0.5*(q_2 * C_{EQCR} * f_{q2})_{\text{routed\_Clk2}} + (r_{2*} f_{q2})_{\text{routed\_Clk2}}(2)]$$

EQ 3

where:

m = Number of logic modules switching at frequency f_m

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

q_1 = Number of clock loads on the first routed array clock

q_2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • **42MX IEEE 1149.1 Boundary Scan Circuitry**

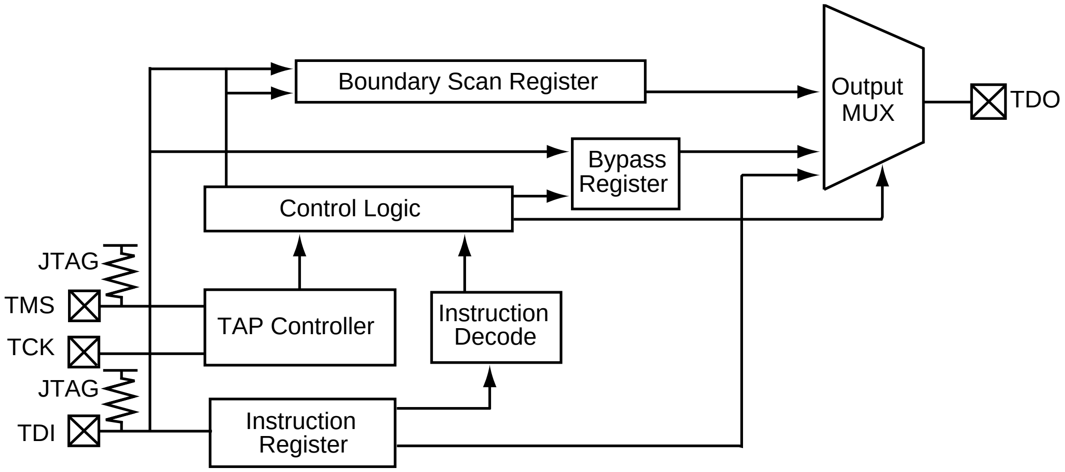


Table 9 • **Test Access Port Descriptions**

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

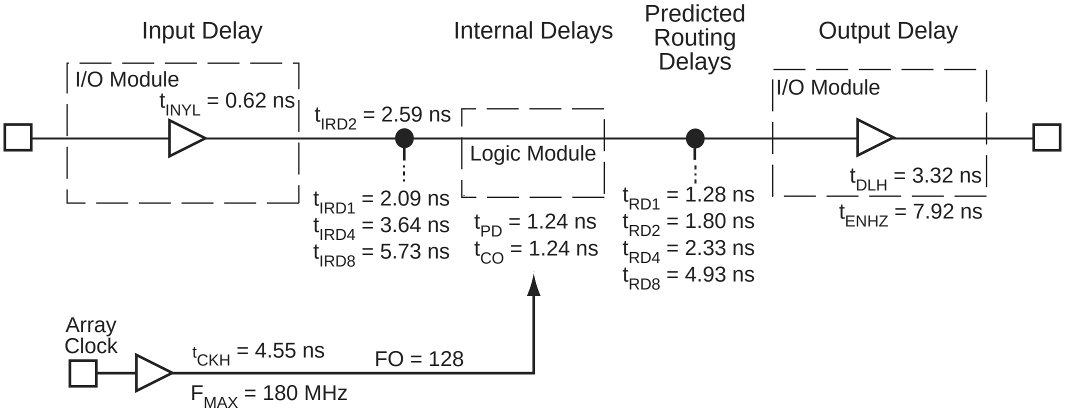
Table 10 • **Supported BST Public Instructions**

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

3.10 Timing Models

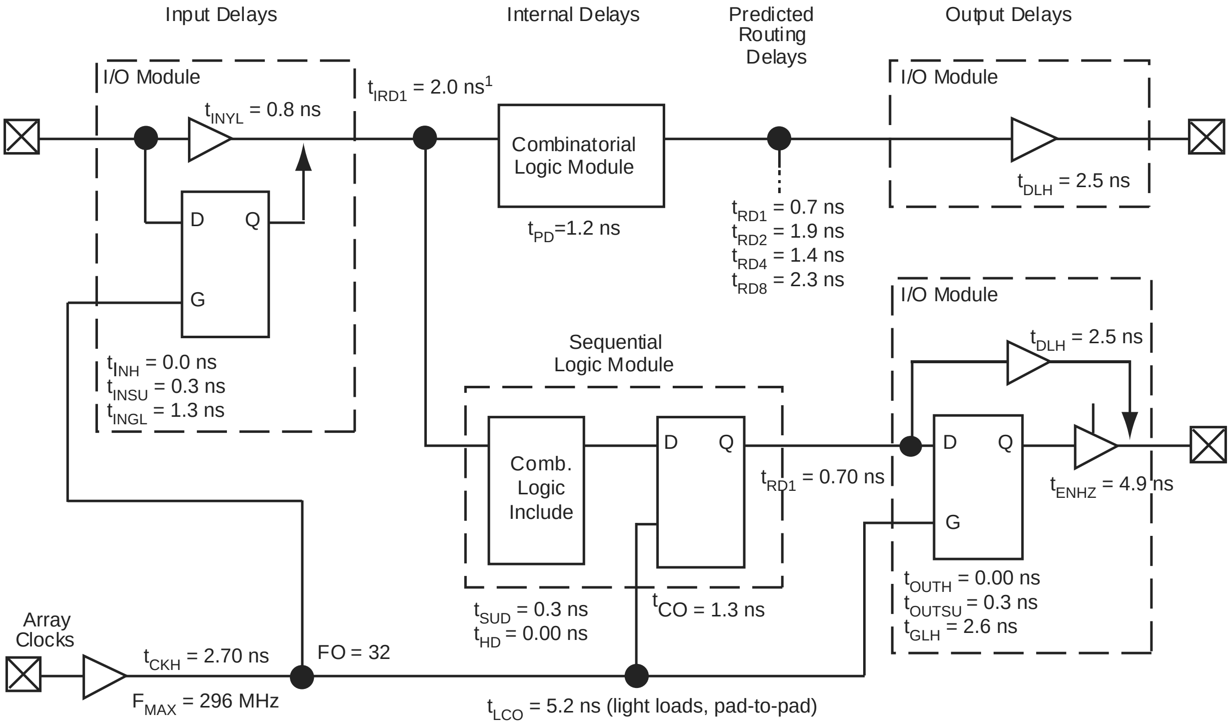
The following figures show various timing models.

Figure 17 • **40MX Timing Model***



Note: Values are shown for 40MX –3 speed devices at 5.0 V worst-case commercial conditions.

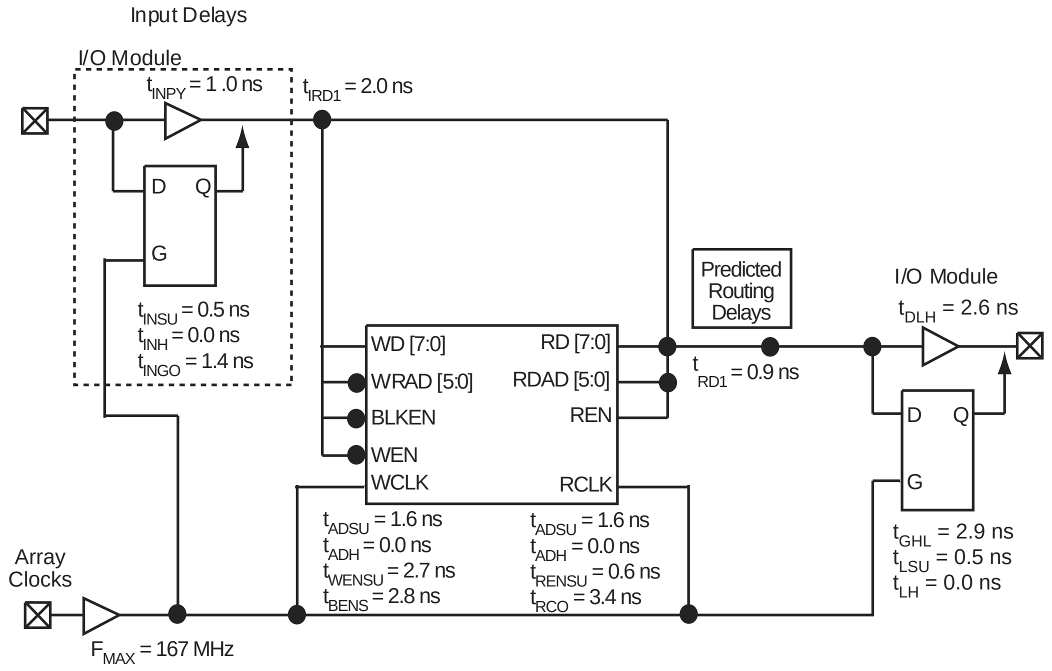
Figure 18 • **42MX Timing Model**



Note: 1. Input module predicted routing delay

Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

Figure 20 • **42MX Timing Model (SRAM Functions)**



Note: Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

The following figures show parameter measurement details.

Figure 21 • **Output Buffer Delays**

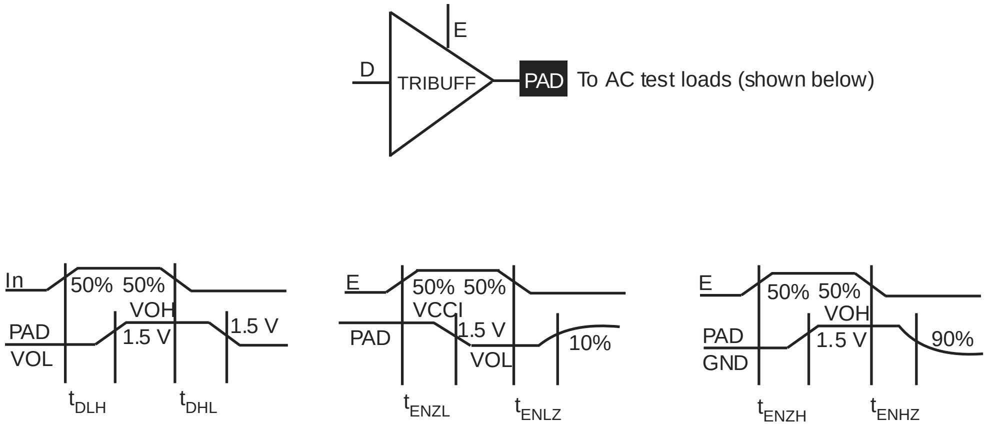


Table 37 • **A40MX04 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t_{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t_{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t_{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d_{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.2		1.3		1.5		1.8		2.5	ns
t_{CO}	Sequential Clock-to-Q		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.8		2.6	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.6		1.8		2.1		2.9	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{RD2}	FO = 2 Routing Delay		0.9		1.0		1.2		1.4		1.9	ns
t_{RD3}	FO = 3 Routing Delay		1.2		1.3		1.5		1.7		2.4	ns
t_{RD4}	FO = 4 Routing Delay		1.4		1.5		1.7		2.0		2.9	ns
t_{RD8}	FO = 8 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns
Logic Module Sequential Timing[3, 4]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.3		0.4		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4		3.8		4.3		5.0		7.0		ns

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
t_{RD4}	FO = 4 Routing Delay		1.9		2.1		2.4		2.9		4.0	ns
t_{RD8}	FO = 8 Routing Delay		3.2		3.6		4.1		4.8		6.7	ns
Logic Module Sequential Timing [3, 4]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5		0.5		0.6		0.7		0.9		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.7		5.3		6.0		7.0		9.8		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.2		6.9		7.8		9.2		12.9		ns
t_A	Flip-Flop Clock Input Period	5.0		5.6		6.2		7.1		9.9		ns
t_{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
t_{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency		161		146		135		117		70	MHz

Table 41 • **A42MX16 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{ACO}	Array Clock-to-Out (Pad-to-Pad),64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros use tPD1 + tRD1 + taped, to + tRD1 + taped, or tPD1 + tRD1 + tusk, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing ansalysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 42 • **A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Combinatorial Functions[1]												
t_{PD}	Internal Array Module Delay		1.2		1.3		1.5		1.8		2.5	ns
t_{PDD}	Internal Decode Module Delay		1.4		1.6		1.8		2.1		3.0	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns
t_{RD3}	FO = 3 Routing Delay		1.3		1.4		1.6		1.9		2.6	ns
t_{RD4}	FO = 4 Routing Delay		1.5		1.7		1.9		2.2		3.1	ns
t_{RD5}	FO = 8 Routing Delay		2.4		2.7		3.0		3.6		5.0	ns
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.2		1.3		1.5		1.8		2.5	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.4		1.6		1.8		2.1		2.9	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.3		6.5		9.0		ns

Table 42 • **A42MX24 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t_{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.9	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t_{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t_{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t_{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.6		6.1		6.9		8.1		11.4	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 45 • **A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t_{IRD2}	FO = 2 Routing Delay			3.2		3.5		4.1		4.8		6.7	ns
t_{IRD3}	FO = 3 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
t_{IRD4}	FO = 4 Routing Delay			4.2		4.6		5.3		6.2		8.7	ns
t_{IRD8}	FO = 8 Routing Delay			6.1		6.8		7.7		9.0		12.6	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32		4.6		5.1		5.7		6.7		9.3	ns
		FO = 635		5.0		5.6		6.3		7.4		10.3	ns
t_{CKL}	Input HIGH to LOW	FO = 32		5.3		5.9		6.7		7.8		11.0	ns
		FO = 635		6.8		7.6		8.6		10.1		14.1	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t_{PWL}	Minimum Pulse Width LOW	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t_{CKSW}	Maximum Skew	FO = 32		1.0		1.2		1.3		1.5		2.2	ns
		FO = 635		1.0		1.2		1.3		1.5		2.2	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	4.0		4.4		5.0		5.9		8.2		ns
		FO = 635	4.6		5.2		5.9		6.9		9.6		ns
t_P	Minimum Period (1/f_{MAX})	FO = 32	9.2		10.2		11.1		12.7		21.2		ns
		FO = 635	9.9		11.0		12.0		13.8		23.0		ns
f_{MAX}	Maximum Datapath Frequency	FO = 32		108		98		90		79		47	MHz
		FO = 635		100		91		83		73		44	MHz
TTL Output Module Timing[5]													
t_{DLH}	Data-to-Pad HIGH			3.6		4.0		4.5		5.3		7.4	ns
t_{DHL}	Data-to-Pad LOW			4.2		4.6		5.2		6.2		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH			3.7		4.2		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW			4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z			7.34		8.2		9.3		10.9		15.3	ns
TTL Output Module Timing[5]													
t_{ENLZ}	Enable Pad LOW to Z			6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH			4.9		5.5		6.2		7.3		10.2	ns
t_{GHL}	G-to-Pad LOW			4.9		5.5		6.2		7.3		10.2	ns
t_{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.9		8.8		10.0		11.8		16.5	ns

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 54 • **PQ240**

PQ240	
Pin Number	**A42MX36 Function**
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

Table 56 • **VQ100**

VQ100		
Pin Number	**A42MX09 Function**	**A42MX16 Function**
93	I/O	I/O
94	GND	GND
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	DCLK, I/O	DCLK, I/O

Figure 48 • **TQ176**

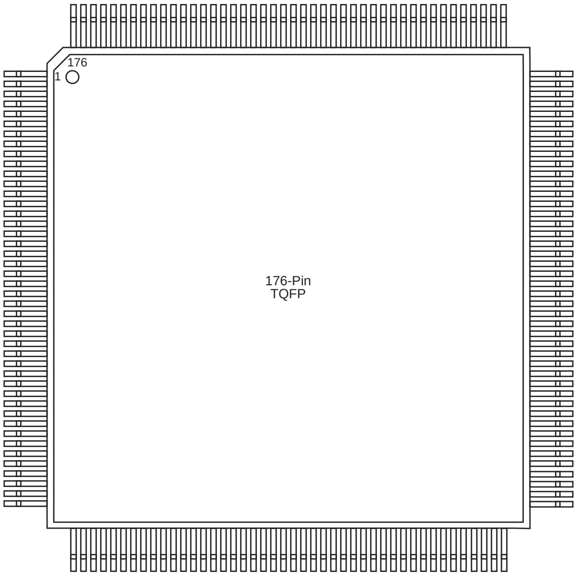


Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
1	GND	GND	GND
2	MODE	MODE	MODE
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	NC	NC	I/O
9	I/O	I/O	I/O

Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
84	I/O	I/O	WD, I/O
85	I/O	I/O	WD, I/O
86	NC	I/O	I/O
87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	I/O	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	NC	NC	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	GND	GND	GND
107	NC	I/O	I/O
108	NC	I/O	TCK, I/O
109	LP	LP	LP
110	VCCA	VCCA	VCCA
111	GND	GND	GND
112	VCCI	VCCI	VCCI
113	VCCA	VCCA	VCCA
114	NC	I/O	I/O
115	NC	I/O	I/O
116	NC	VCCA	VCCA
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O

Figure 50 • **CQ256**

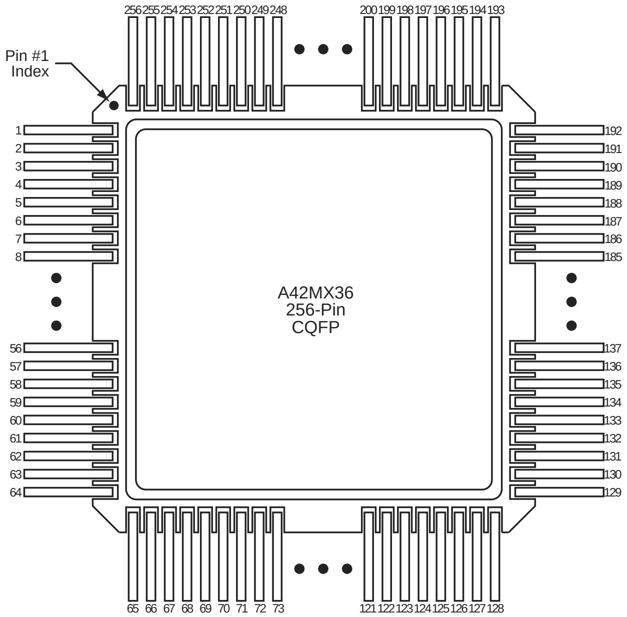


Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
1	NC
2	GND
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	GND
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O

Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
170	VCCA
171	I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	I/O
177	I/O
178	I/O
179	I/O
180	GND
181	I/O
182	I/O
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	MODE
189	VCCA
190	GND
191	NC
192	NC
193	NC
194	I/O
195	DCLK, I/O
196	I/O
197	I/O
198	I/O
199	WD, I/O
200	WD, I/O
201	VCCI
202	I/O
203	I/O
204	I/O
205	I/O
206	GND

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
B3	I/O
A2	I/O
C3	DCLK
B5	GNDA
E12	GNDA
J2	GNDA
M9	GNDA
B9	GNDI
C5	GNDI
E11	GNDI
F4	GNDI
J3	GNDI
J11	GNDI
L5	GNDI
L9	GNDI
C9	GNDQ
E3	GNDQ
K12	GNDQ
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI